Book chapters


Journal articles


Conference papers

12. H. C. Sio, S. P Phang, T. Trupke and D. Macdonald, “Electrical properties of different types of grain boundaries in multicrystalline silicon by photoluminescence imaging”, Proceedings of the


65. Daniel Macdonald, Andrés Cuevas, Keith McIntosh, Laetitia Barbosa and Denis De Ceuster, “Impact of Cr, Fe, Ni, Ti and W surface contamination on diffused and oxidised n-type crystalline


